



ESD



TVS



MOS



LDO



Diode



Sensor



DC-DC

Product Specification

▶ Domestic Part Number	AO6604
▶ Overseas Part Number	AO6604
▶ Equivalent Part Number	AO6604



N + P Channel MOSFET**General Description**

The AO6604 combines advanced trench MOSFET technology with a low resistance package to provide extremely low $R_{DS(ON)}$. This device is ideal for load switch and battery protection applications.

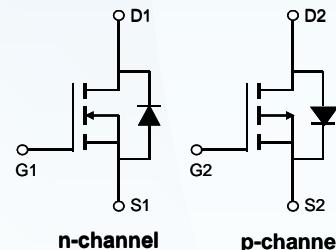
Product Summary

N-Ch:

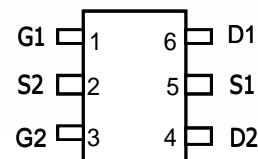
- $V_{DS(V)}=20V$
- $R_{DS(ON)} < 65m\Omega$ ($V_{GS} = 4.5V$)
- $R_{DS(ON)} < 75 m\Omega$ ($V_{GS} = 2.5V$)
- $R_{DS(ON)} < 100m\Omega$ ($V_{GS} = 1.8V$)

P-Ch:

- $V_{DS(V)}=-20V$
- $R_{DS(ON)} < 75m\Omega$ ($V_{GS} = -4.5V$)
- $R_{DS(ON)} < 95m\Omega$ ($V_{GS} = -2.5V$)
- $R_{DS(ON)} < 115m\Omega$ ($V_{GS} = -1.8V$)



n-channel p-channel



SOT23-6

Absolute Maximum Ratings $T_A=25^\circ C$ unless otherwise noted

Parameter	Symbol	Max n-channel	Max p-channel	Units
Drain-Source Voltage	V_{DS}	20	-20	V
Gate-Source Voltage	V_{GS}	± 8	± 8	V
Continuous Drain Current	I_D	3.4	-2.5	A
$T_A=70^\circ C$		2.5	-2	
Pulsed Drain Current ^c	I_{DM}	13	-13	
Power Dissipation ^B	P_D	1.1	1.1	W
$T_A=25^\circ C$		0.7	0.7	
Junction and Storage Temperature Range	T_J, T_{STG}	-55 to 150		°C

Thermal Characteristics

Parameter	Symbol	Typ	Max	Units
Maximum Junction-to-Ambient ^A	$R_{\theta JA}$	78	110	°C/W
Maximum Junction-to-Ambient ^{A,D}		106	150	°C/W
Maximum Junction-to-Lead	$R_{\theta JL}$	64	80	°C/W

N+ P Channel MOSFET

N-Channel Electrical Characteristics ($T_J=25^\circ\text{C}$ unless otherwise noted)

Symbol	Parameter	Conditions	Min	Typ	Max	Units
STATIC PARAMETERS						
BV_{DSS}	Drain-Source Breakdown Voltage	$I_D=250\mu\text{A}, V_{GS}=0\text{V}$	20			V
I_{DSS}	Zero Gate Voltage Drain Current	$V_{DS}=20\text{V}, V_{GS}=0\text{V}$			1	μA
I_{GSS}	Gate-Body leakage current	$V_{DS}=0\text{V}, V_{GS}= \pm 8\text{V}$			± 100	nA
$V_{GS(\text{th})}$	Gate Threshold Voltage	$V_{DS}=V_{GS}, I_D=250\mu\text{A}$	0.4	0.7	1	V
$I_{D(\text{ON})}$	On state drain current	$V_{GS}=4.5\text{V}, V_{DS}=5\text{V}$	13			A
$R_{DS(\text{ON})}$	Static Drain-Source On-Resistance	$V_{GS}=4.5\text{V}, I_D=3.4\text{A}$		51	65	$\text{m}\Omega$
		$V_{GS}=2.5\text{V}, I_D=3\text{A}$		58	75	$\text{m}\Omega$
		$V_{GS}=1.8\text{V}, I_D=2\text{A}$		68	100	$\text{m}\Omega$
g_{FS}	Forward Transconductance	$V_{DS}=5\text{V}, I_D=3.4\text{A}$		16		S
V_{SD}	Diode Forward Voltage	$I_S=1\text{A}, V_{GS}=0\text{V}$		0.7	1	V
I_S	Maximum Body-Diode Continuous Current				1.5	A
DYNAMIC PARAMETERS						
C_{iss}	Input Capacitance	$V_{GS}=0\text{V}, V_{DS}=10\text{V}, f=1\text{MHz}$	205	260	320	pF
C_{oss}	Output Capacitance		33	48	63	pF
C_{rss}	Reverse Transfer Capacitance		16	27	38	pF
R_g	Gate resistance	$V_{GS}=0\text{V}, V_{DS}=0\text{V}, f=1\text{MHz}$	1.5	3	4.5	Ω
SWITCHING PARAMETERS						
$Q_g(4.5\text{V})$	Total Gate Charge	$V_{GS}=4.5\text{V}, V_{DS}=10\text{V}, I_D=3.4\text{A}$		2.9	3.8	nC
Q_{gs}	Gate Source Charge			0.4		nC
Q_{gd}	Gate Drain Charge			0.6		nC
$t_{D(\text{on})}$	Turn-On DelayTime	$V_{GS}=5\text{V}, V_{DS}=10\text{V}, R_L=2.95\Omega, R_{\text{GEN}}=3\Omega$		2.5		ns
t_r	Turn-On Rise Time			3.2		ns
$t_{D(\text{off})}$	Turn-Off DelayTime			21		ns
t_f	Turn-Off Fall Time			3		ns
t_{rr}	Body Diode Reverse Recovery Time	$I_F=3.4\text{A}, dI/dt=100\text{A}/\mu\text{s}$		14	19	ns
Q_{rr}	Body Diode Reverse Recovery Charge	$I_F=3.4\text{A}, dI/dt=100\text{A}/\mu\text{s}$		3.8		nC

A. The value of R_{QA} is measured with the device mounted on 1in² FR-4 board with 2oz. Copper, in a still air environment with $T_A = 25^\circ\text{C}$. The value in any given application depends on the user's specific board design.

B. The power dissipation P_D is based on $T_{J(\text{MAX})}=150^\circ\text{C}$, using $\leq 10\text{s}$ junction-to-ambient thermal resistance.

C. Repetitive rating, pulse width limited by junction temperature $T_{J(\text{MAX})}=150^\circ\text{C}$. Ratings are based on low frequency and duty cycles to keep initial $T_J=25^\circ\text{C}$.

D. The R_{QA} is the sum of the thermal impedance from junction to lead R_{QJL} and lead to ambient.

E. The static characteristics in Figures 1 to 6 are obtained using <300 μs pulses, duty cycle 0.5% max.

F. These curves are based on the junction-to-ambient thermal impedance which is measured with the device mounted on 1in² FR-4 board with 2oz. Copper, assuming a maximum junction temperature of $T_{J(\text{MAX})}=150^\circ\text{C}$. The SOA curve provides a single pulse rating.

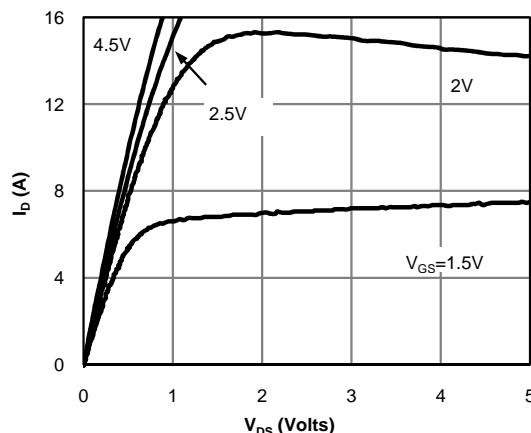
N + P Channel MOSFET
N-Channel: TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS


Fig 1: On-Region Characteristics (Note E)

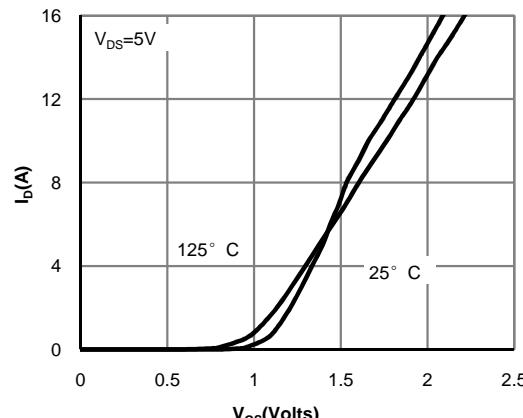


Figure 2: Transfer Characteristics (Note E)

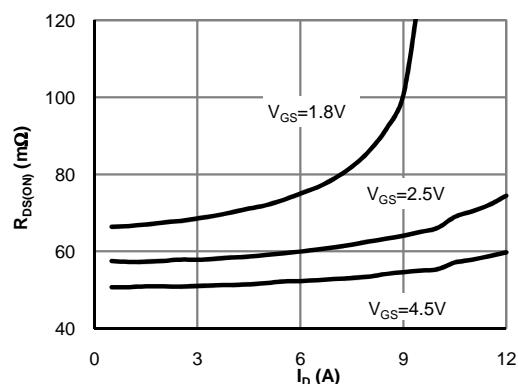


Figure 3: On-Resistance vs. Drain Current and Gate Voltage (Note E)

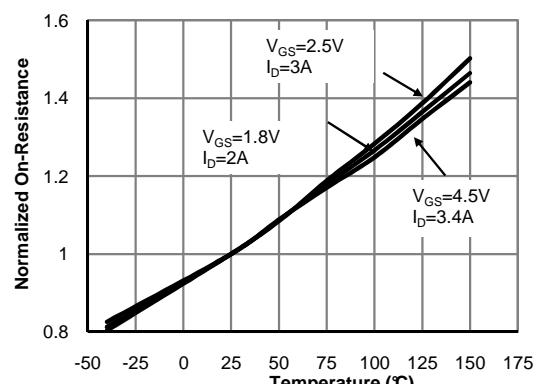


Figure 4: On-Resistance vs. Junction Temperature (Note E)

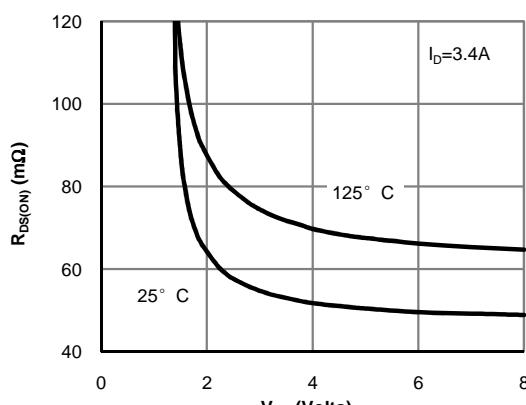


Figure 5: On-Resistance vs. Gate-Source Voltage (Note E)

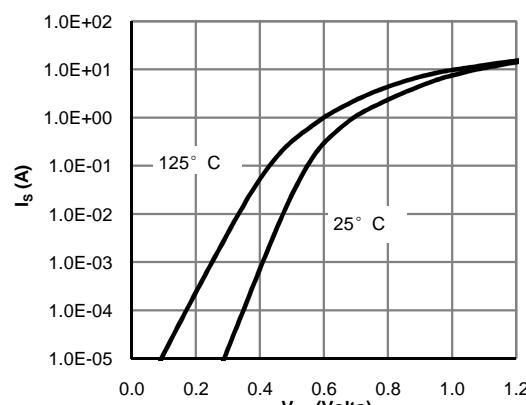


Figure 6: Body-Diode Characteristics (Note E)

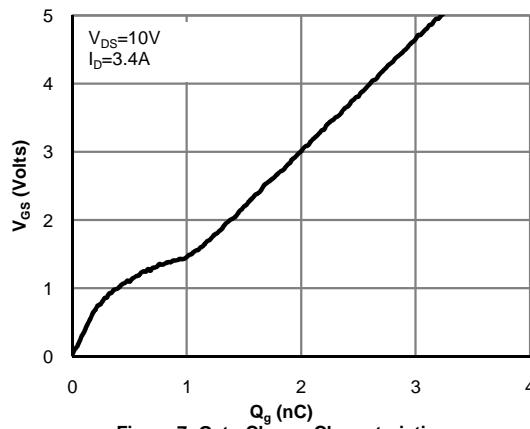
N-Channel: TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS


Figure 7: Gate-Charge Characteristics

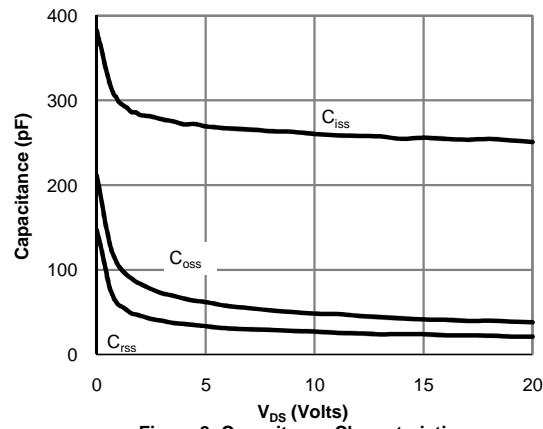


Figure 8: Capacitance Characteristics

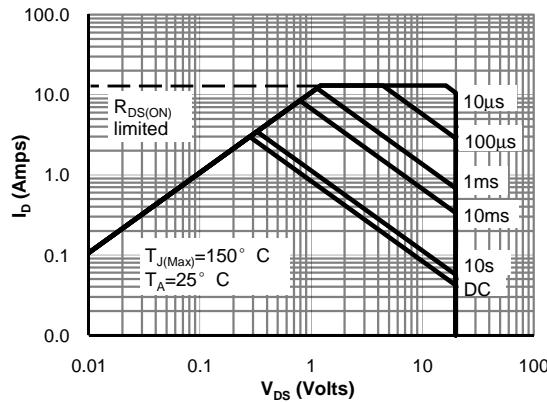


Figure 9: Maximum Forward Biased Safe Operating Area (Note F)

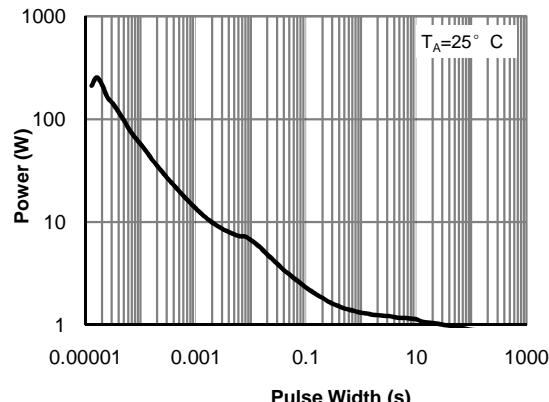
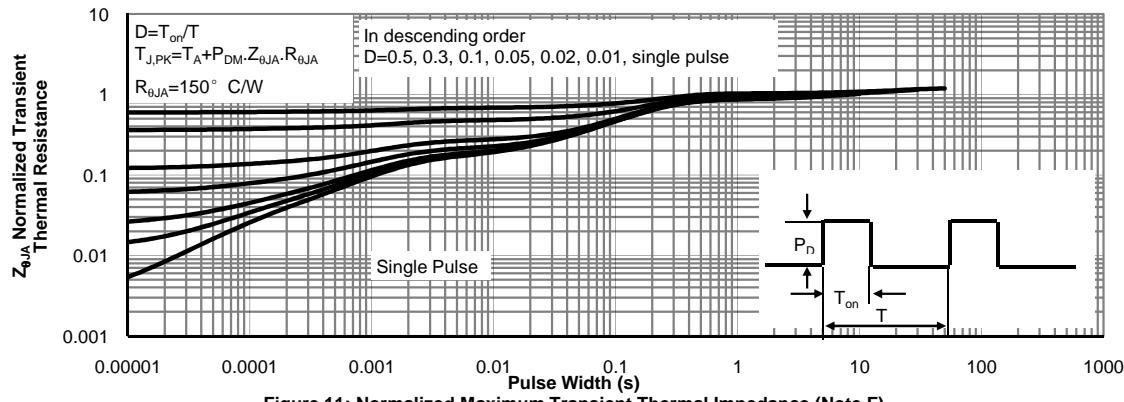
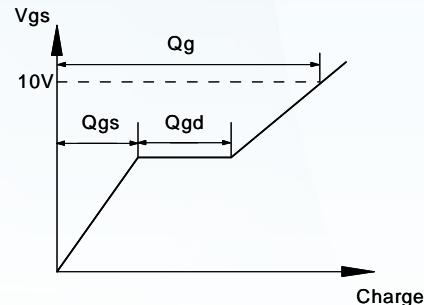
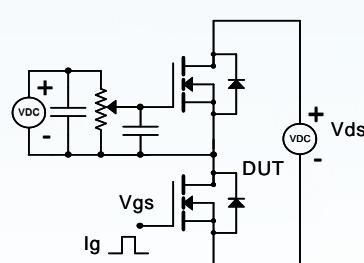


Figure 10: Single Pulse Power Rating Junction-to-Ambient (Note F)

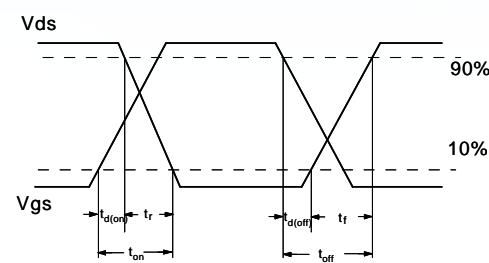
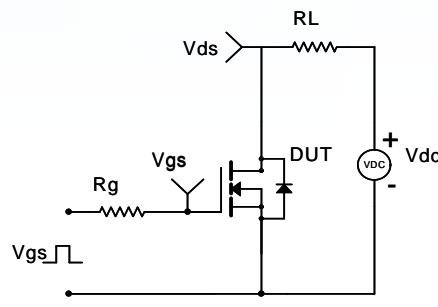


N + P Channel MOSFET

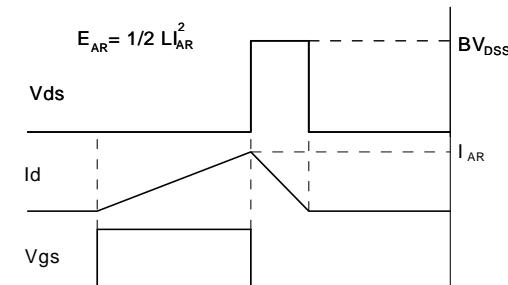
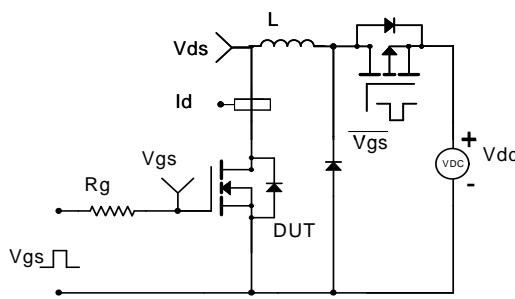
Gate Charge Test Circuit & Waveform



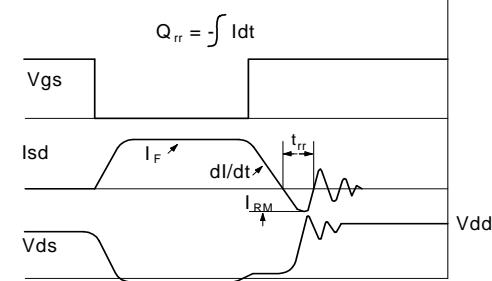
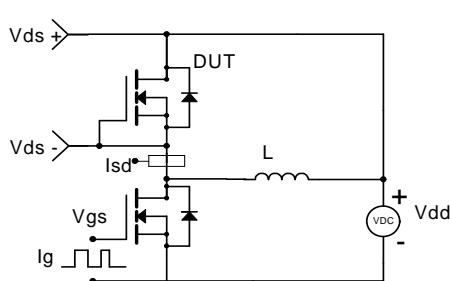
Resistive Switching Test Circuit & Waveforms



Unclamped Inductive Switching (UIS) Test Circuit & Waveforms



Diode Recovery Test Circuit & Waveforms



N+ P Channel MOSFET

P-Channel Electrical Characteristics ($T_J=25^\circ\text{C}$ unless otherwise noted)

Symbol	Parameter	Conditions	Min	Typ	Max	Units
STATIC PARAMETERS						
BV_{DSS}	Drain-Source Breakdown Voltage	$I_D=-250\mu\text{A}, V_{GS}=0\text{V}$	-20			V
I_{DSS}	Zero Gate Voltage Drain Current	$V_{DS}=-20\text{V}, V_{GS}=0\text{V}$			-1	μA
		$T_J=55^\circ\text{C}$			-5	
I_{GSS}	Gate-Body leakage current	$V_{DS}=0\text{V}, V_{GS}= \pm 8\text{V}$			± 100	nA
$V_{GS(\text{th})}$	Gate Threshold Voltage	$V_{DS}=V_{GS}, I_D=-250\mu\text{A}$	-0.4	-0.65	-1	V
$I_{D(\text{ON})}$	On state drain current	$V_{GS}=-4.5\text{V}, V_{DS}=-5\text{V}$	-13			A
$R_{DS(\text{ON})}$	Static Drain-Source On-Resistance	$V_{GS}=-4.5\text{V}, I_D=-2.5\text{A}$		56	75	$\text{m}\Omega$
		$V_{GS}=-2.5\text{V}, I_D=-2\text{A}$		70	95	$\text{m}\Omega$
		$V_{GS}=-1.8\text{V}, I_D=-1\text{A}$		85	115	$\text{m}\Omega$
g_{FS}	Forward Transconductance	$V_{DS}=-5\text{V}, I_D=-2.5\text{A}$		13		S
V_{SD}	Diode Forward Voltage	$I_S=-1\text{A}, V_{GS}=0\text{V}$		-0.7	-1	V
I_S	Maximum Body-Diode Continuous Current				-1.5	A
DYNAMIC PARAMETERS						
C_{iss}	Input Capacitance	$V_{GS}=0\text{V}, V_{DS}=-10\text{V}, f=1\text{MHz}$		560	745	pF
C_{oss}	Output Capacitance			80		pF
C_{rss}	Reverse Transfer Capacitance			70		pF
R_g	Gate resistance	$V_{GS}=0\text{V}, V_{DS}=0\text{V}, f=1\text{MHz}$		15	23	Ω
SWITCHING PARAMETERS						
$Q_g(4.5\text{V})$	Total Gate Charge	$V_{GS}=-4.5\text{V}, V_{DS}=-10\text{V}, I_D=-2.5\text{A}$		8.5	11	nC
Q_{gs}	Gate Source Charge			1.2		nC
Q_{gd}	Gate Drain Charge			2.1		nC
$t_{D(\text{on})}$	Turn-On DelayTime	$V_{GS}=-4.5\text{V}, V_{DS}=-10\text{V}, R_L=4\Omega, R_{\text{GEN}}=6\Omega$		7.2		ns
t_r	Turn-On Rise Time			36		ns
$t_{D(\text{off})}$	Turn-Off DelayTime			53		ns
t_f	Turn-Off Fall Time			56		ns
t_{rr}	Body Diode Reverse Recovery Time	$I_F=-2.5\text{A}, dI/dt=100\text{A}/\mu\text{s}$		37	49	ns
Q_{rr}	Body Diode Reverse Recovery Charge	$I_F=-2.5\text{A}, dI/dt=100\text{A}/\mu\text{s}$		27		nC

A. The value of R_{QA} is measured with the device mounted on 1in² FR-4 board with 2oz. Copper, in a still air environment with $T_A = 25^\circ\text{C}$. The value in any given application depends on the user's specific board design.

B. The power dissipation P_D is based on $T_{J(\text{MAX})}=150^\circ\text{C}$, using $\leq 10\text{s}$ junction-to-ambient thermal resistance.

C. Repetitive rating, pulse width limited by junction temperature $T_{J(\text{MAX})}=150^\circ\text{C}$. Ratings are based on low frequency and duty cycles to keep initial $T_J=25^\circ\text{C}$.

D. The R_{QA} is the sum of the thermal impedance from junction to lead R_{JL} and lead to ambient.

E. The static characteristics in Figures 1 to 6 are obtained using <300 μs pulses, duty cycle 0.5% max.

F. These curves are based on the junction-to-ambient thermal impedance which is measured with the device mounted on 1in² FR-4 board with 2oz. Copper, assuming a maximum junction temperature of $T_{J(\text{MAX})}=150^\circ\text{C}$. The SOA curve provides a single pulse rating.

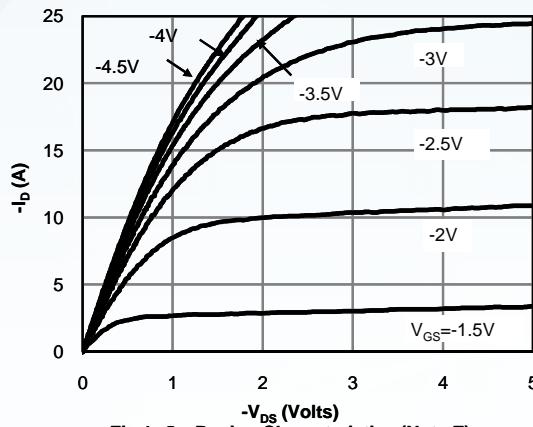
P-Channel: TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS
N + P Channel MOSFET


Fig 1: On-Region Characteristics (Note E)

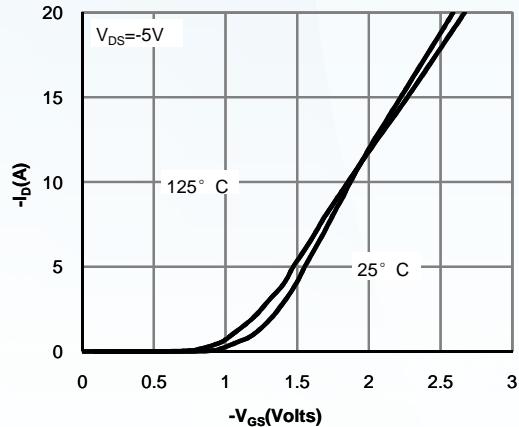


Figure 2: Transfer Characteristics (Note E)

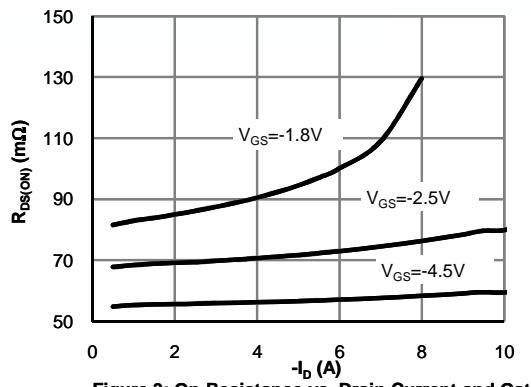


Figure 3: On-Resistance vs. Drain Current and Gate Voltage (Note E)

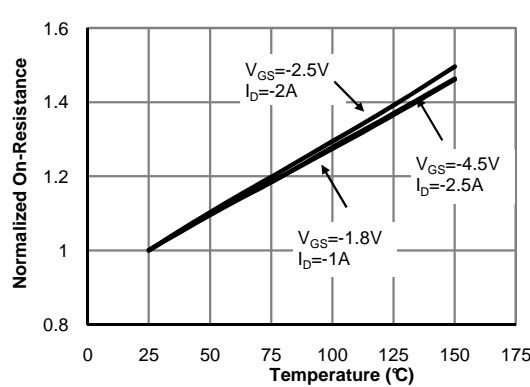


Figure 4: On-Resistance vs. Junction Temperature (Note E)

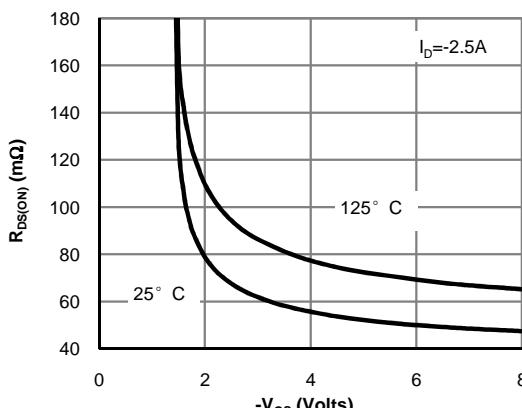


Figure 5: On-Resistance vs. Gate-Source Voltage (Note E)

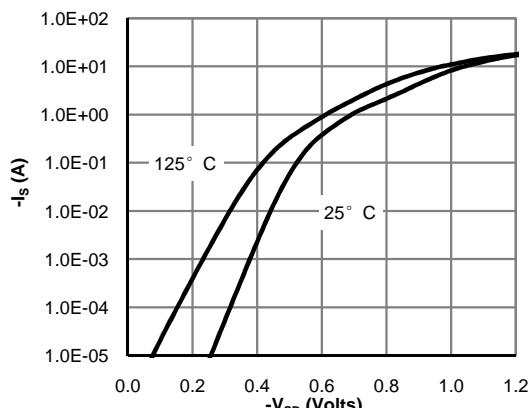
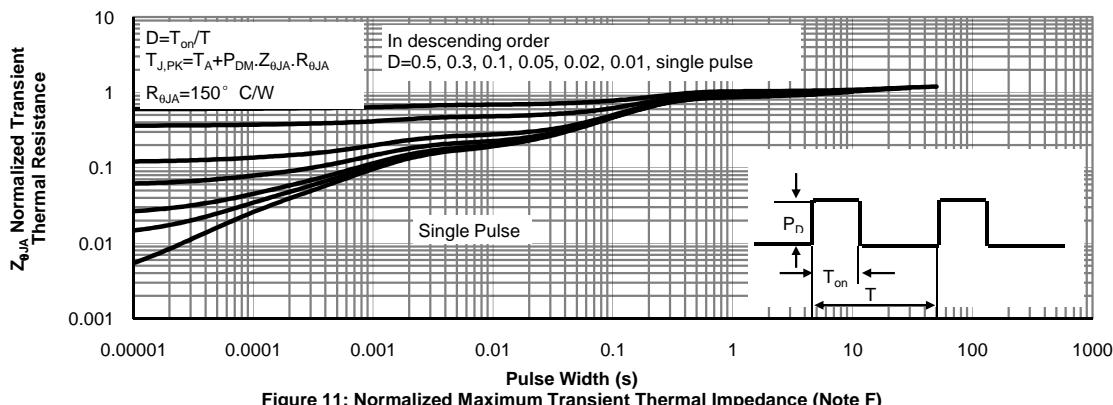
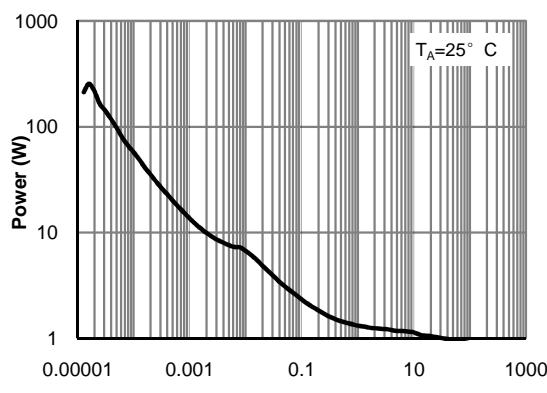
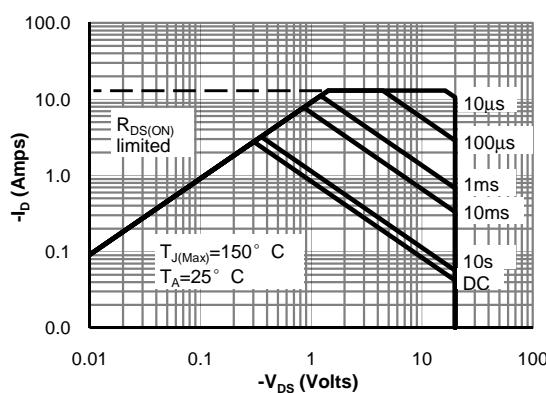
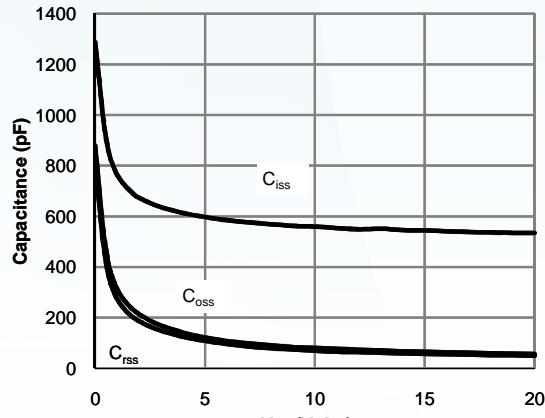
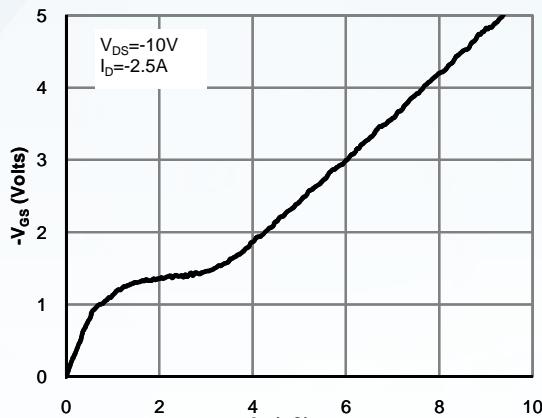
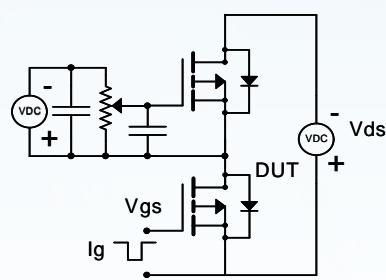


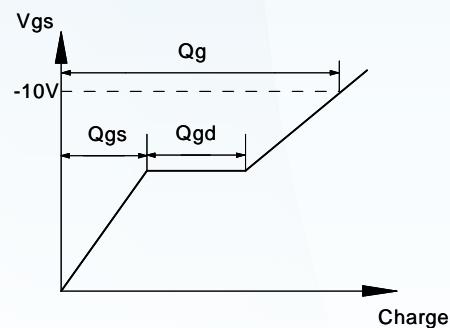
Figure 6: Body-Diode Characteristics (Note E)

N + P Channel MOSFET
P-Channel: TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS


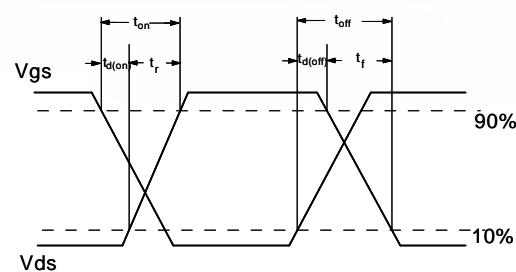
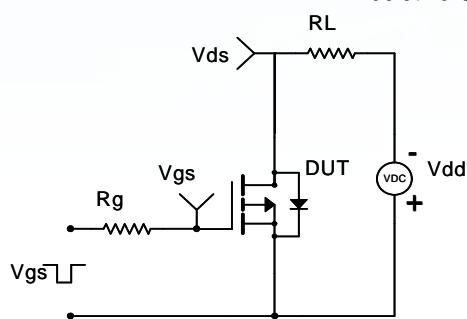
Gate Charge Test Circuit & Waveform



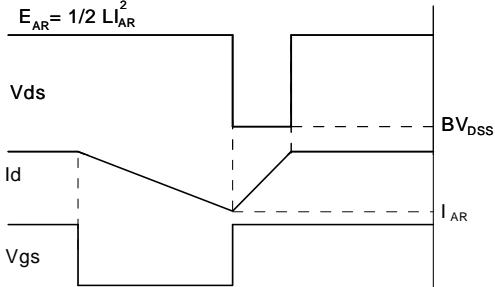
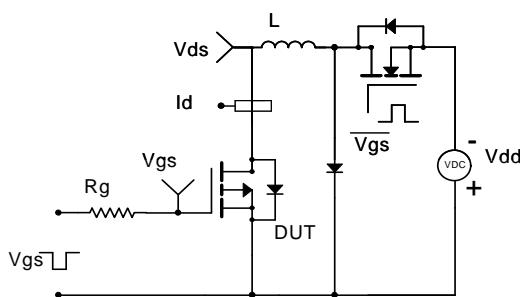
N + P Channel MOSFET



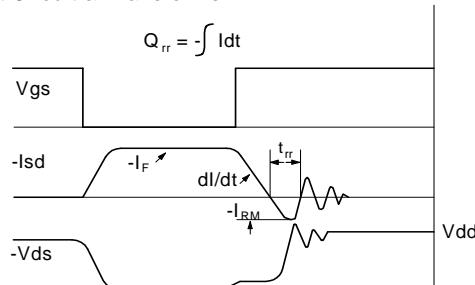
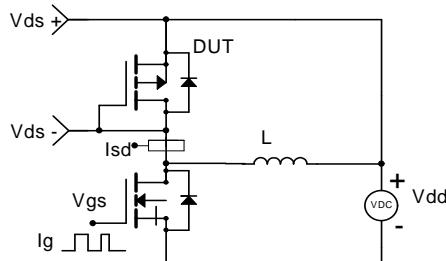
Resistive Switching Test Circuit & Waveforms

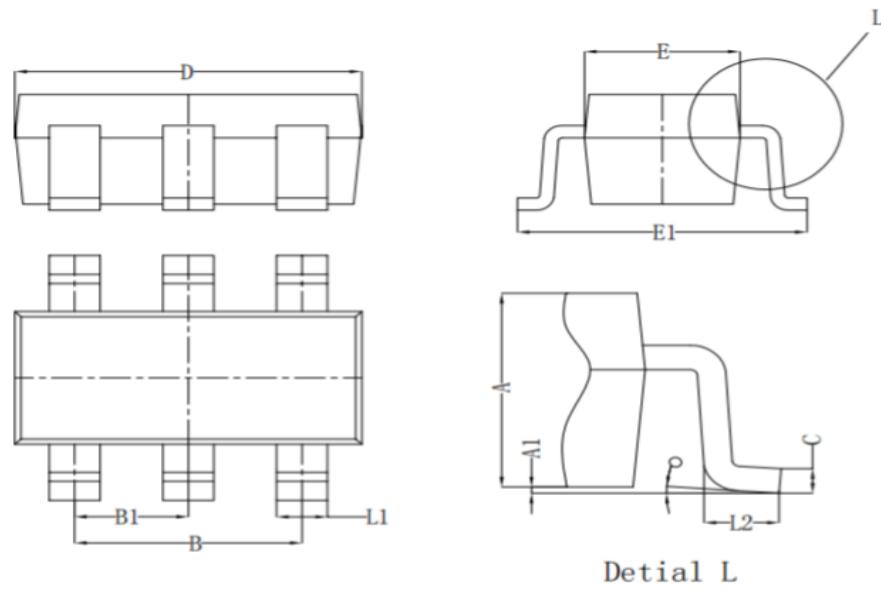


Unclamped Inductive Switching (UIS) Test Circuit & Waveforms



Diode Recovery Test Circuit & Waveforms

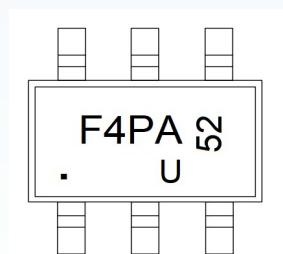


N + P Channel MOSFET**SOT23- 6 PACKAGE OUTLINE DIMENSIONS**

Detail L

Symbol	Dim in mm		
	Min	Nor	Max
A	1.050	1.100	1.150
A1	0.000	0.050	0.100
L1	0.300	0.400	0.500
C	0.100	0.150	0.200
D	2.820	2.920	3.020
E	1.500	1.600	1.700
E1	2.650	2.800	2.950
B	1.800	1.900	2.000
B1	0.950 TYP		
L2	0.300	0.450	0.600
o	0°	4°	8°

N+ P Channel MOSFET

Marking**Ordering information**

Order code	Package	Baseqty	Deliverymode
AO6604	SOT23-6	3000	Tape and reel

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